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<b>Notice of References Cited</b>	Application/Control No. 09/759,414	Applicant(s)/Patent Under Reexamination LI, ZHE	
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	C	US-5,469,367	11-1995	Puri et al.	716/18
	D	US-5,923,569	07-1999	Kumashiro et al.	716/7
	E	US-5,752,000	05-1998	McGeer et al.	703/14
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**NON-PATENT DOCUMENTS**

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	W	Lin-C.C. et al. " Logic Synthesis for Engineering Change" IEEE March 1999, pp.282-292.
	X	Huang-S.Y. et al. "Fault Simulation based Design Error Diagnosis for Sequential Circuits" ACM June 1998, pp.632-637

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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